

<b>Notice of References Cited</b>	Application/Control No. 09/886,362	Applicant(s)/Patent Under Reexamination INNES ET AL.	
	Examiner Jonathan G. Sterrett	Art Unit 3623	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Breitfelder, Kim; Messina, Don; "The Authoritative Dictionary of IEEE Standards Terms", 7th Edition, Copyright 2000, IEEE Press, p. 270.			
	V	Merriam-Websters Collegiate Dictionary, 10th edition, Copyright 1997, p.1 & 746.			
	W	Gilchrist, Warren, "Modelling failure modes and effects analysis", 1993, The International Journal of Quality and Reliability Management, Bradford, Vol. 10, Iss 5, p.16, ProQuest ID 1123094.			
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